

NPN Transistor Bare Die, 2N3020

Rev 1.0 21/10/24

General purpose medium power amplifier or switch in bare die form Complement PNP 2N4033

Features:

- Collector current up to 1A
- Low Leakage Current & Saturation Voltage
- Characterized at temperature extremes
- High Reliability Gold Back Metal
- High Reliability tested grades for Military + Space

Ordering Information:

The following part suffixes apply:

- No suffix MIL-STD-750 /2072 Visual Inspection
- "H" MIL-STD-750 /2072 Visual Inspection+ MIL-STD-38534 Class H LAT
- "K" MIL-STD-750 /2072 Visual Inspection+ MIL-STD-38534 Class K LAT

LAT = Lot Acceptance Test.

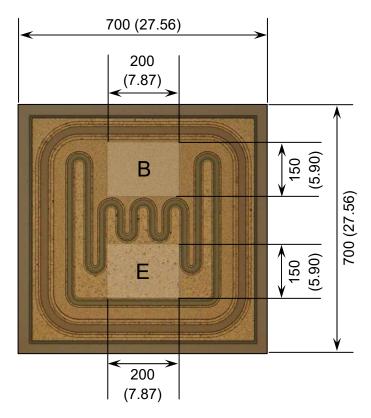
For further information on LAT process flows see below.

www.siliconsupplies.com\quality\bare-die-lot-qualification

Supply Formats:

- Default Die in Waffle Pack (400 per tray capacity)
- Sawn Wafer on Tape Specific request
- Unsawn Wafer Specific request
- With additional electrical selection Specific request
- Sawn as pairs or adjacent pair pick Specific request

Die Dimensions in µm (mils)



E = EMITTER **B** = BASE

DIE BACK = COLLECTOR

Mechanical Specification

Die Size (Excluding Saw Street)	700 x 700 27.56 x 27.56	μm mils	
Base & Emitter Pad Size	200 x 150 7.87 x 5.90	μm mils	
Die Thickness	180 (±20) 7.09 (±0.79)	μm mils	
Top Metal Composition	Al - 3µm		
Back Metal Composition	Au - 0.9μm		





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Absolute Maximum Ratings¹ T_A = 25°C unless otherwise stated

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PARAMETER	SYMBOL	VALUE	UNIT
Collector-Base Voltage	V _{CBO}	140	V
Collector-Emitter Voltage	V _{CEO}	80	V
Emitter-Base Voltage	V _{EBO}	7	V
Collector Current	I _C	1	Α
Junction Temperature	TJ	150	°C
Storage Temperature	T _{stg}	-55 to 150	°C

Electrical Characteristics T_A = 25°C unless otherwise stated

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNIT
OFF CHARACTERISTICS						
Collector-Base Breakdown Voltage ²	V _{(BR)CBO}	$I_C = 100 \mu A, I_E = 0$	140	-	-	V
Collector-Emitter Breakdown Voltage	V _{(BR)CEO}	I _C = 30mA, I _B = 0	80	-	-	V
Emitter-Base Breakdown Voltage	V _{(BR)EBO}	$I_E = 100 \mu A, I_C = 0$	7	-	-	V
Collector Cut-off Current	I _{CBO}	$V_{CB} = 90V, I_{E} = 0$	-	-	0.01	μA
		$V_{CB} = 90V, I_{E} = 0, T_{A} = 150^{\circ}C^{3}$	-	-	10	μA
Emitter Cut-off Current	I _{EBO}	$V_{EB} = 5V, I_{C} = 0$	-	-	0.01	μA
ON CHARACTERISTICS						
Forward-Current Transfer Ratio	h _{FE}	$V_{CE} = 10V, I_{C} = 0.1mA$	30	-	200	-
		V _{CE} = 10V, I _C = 10mA	40	-	200	-
		V _{CE} = 10V, I _C = 150mA	40	-	200	-
		$V_{CE} = 10V, I_{C} = 500 \text{mA}^2$	30	-	120	-
		$V_{CE} = 10V, I_{C} = 1A^{2}$	15	-	-	-
Collector-Emitter Saturation Voltage	V _{CE(sat)}	I _C = 150mA, I _B = 15 mA	-	-	0.2	V
		I _C = 500mA, I _B = 50mA	-	-	0.5	V
Base-Emitter Saturation Voltage	V _{BE(sat)}	$I_C = 10$ mA, $I_B = 1$ mA	-	-	1.1	V
		I _C = 150mA, I _B = 15mA	-	-	1.1	V
SMALL SIGNAL CHARACTERISTICS						
Current Gain – Bandwidth Product	f _T	$V_{CE} = 10V, I_{C} = 50mA, f = 20MHz$	100	-	-	MHz
Output Capacitance	C _{obo}	V _{CB} = 10V, I _E = 0, f = 1MHz	-	-	12	pF
Input Capacitance	C _{ibo}	$V_{BE} = 0.5V, I_{C} = 0, f = 1MHz$	-	-	60	
Small-Signal Current Gain	h _{fe}	$V_{CE} = 5V$, $I_C = 1mA$, $f = 1MHz$	80	-	400	
Collector Base Time Constant	rb'C _c	V _{CB} = 10V, I _E = 10mA, f = 4MHz	-	-	400	pS

^{1.} These ratings are limiting values above which the serviceability of any semiconductor device may be impaired. 2. Pulse Test: Pulse Width $\leq 300 \, \mu s$, Duty Cycle $\leq 1\%$ 3. Not production testing in die form, characterized by chip design and package verification





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